REMARKS

Applicant resubmits certain amendments to the claims that were submitted in response to the Office Action. Since the Office Action made the rejections of the claims final, the Examiner did not enter the amendments asserting that the amendments raise new issues that would require further consideration and/or search.

In the Office Action claims 1-25 were rejected under 35 U.S.C. §101 rejections. Applicant submits amendments to the claims for the purpose of advancing prosecution. As amended, independent claim 1 now additionally requires that the step of defining force field vectors includes generating a model of force fields, wherein the step of matching includes manipulating said model to obtain a desired fit between said measured point locations and said template point locations now recite further elements. The model of force field vectors is discussed at, *inter alia*, page 6, lines 18-24. This model represents a tangible result produced during rigid point matching measured points to template points.

As amended, independent claims 11, 18 and 23 now additionally require generation and manipulation of a model comprising a plurality of define force field vectors. The model of force field vectors is discussed at, *inter alia*, page 6, lines 18-24. This model represents a tangible result produced during rigid point matching measured points to template points.

Nevertheless, the Advisory Action alleges that "generating a model would not appear to be sufficient to constitute a tangible result, since the outcome of the generating step has not been used in a disclosed practical application..." Applicant disagrees and respectfully submits that, given the opportunity to conduct the required further search and consideration, the amended claims will be found to be patentable. Practical applications of the disclosed methods are described in context of identifying problems in the prior art. For example:

> One such technology is probe card analysis, in which ***planarity and alignment of a plurality of probes*** arranged in an array ***may be tested or calibrated*** through comparison with a known location of one or more fiducial marks, for example, disposed on or integrated into the structure of a fiducial plate. In particular, some probe card analysis systems employ optical or image data acquired by a camera or other imaging apparatus; in some cases, the imaging apparatus may be disposed on the opposite side of a substantially transparent fiducial plate from the probe array associated with the probe card. These acquired data are representative of both probe tips and fiducial marks, and data processing may be employed which seek to identify position and orientation of probe tips relative to each other through comparison with the known position and orientation of one or more fiducial marks. Alternatively, the position and orientation of imaged

> probe tips may be compared to ideal position and orientation data maintained in the template or reference data set.

Specification at page 1, lines 19-28 (with emphasis added). Issues and shortcomings of methods used to test or calibrate a probe array are then identified. It will be appreciated that the detailed description of the invention discloses methods for resolving the shortcomings in the prior art and the claimed methods are clearly applicable in the calibrating and testing probe arrays.

For example, Applicant respectfully submits that a skilled artisan would obtain practical benefit from using the claimed model of force field vectors as a basis for quickly and precisely calibrating an array of test probes. Applicant further submits that the claimed methods of point matching efficiently produce a test result of alignment of an array of probes expressed as force field vectors and can precisely identify misalignment of probes and array.

Therefore, Applicant respectfully submits that the §101 rejections are improper and expressly obviated by the claims as amended and that the Application is in condition for allowance. Applicant therefore respectfully requests a notice of allowance be issued in this Application. Please charge any fees associated with the submission of this paper to Deposit Account Number 033975. The Commissioner for Patents is also authorized to credit any over payments to the above-referenced Deposit Account.

Respectfully submitted,
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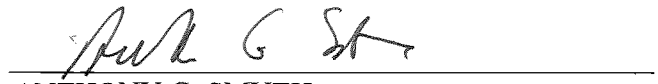

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